

HINWEIS: Die Formelsammlung ist eine einfache Mitschrift, sehr ungeordnet und kann grobe Fehler enthalten. Sie dient lediglich als Überblick zum Fach. Wenn jemand die FS ergänzen/überarbeiten möchte, einfach melden

Wichtige Begriffe:	dispersion lattice impurities to scatter	Verteilung Kristallgitter Fremdstoffe streuen
Abkürzungen:	CVD CNT DoS HOPG PMMA STM	chemical vapour deposition carbon nanotube Density of States Highly Ordered Pyrolytic Graphite Polymethylmethacrylat (Acrylglass) Scanning tunneling microscope

1. Moores Law – scaling

1. Transistormaterial: Germanium
 Transistor scaling 22nm between drain and source of a MOSFET scaling cant continue indefinitely Against Moores Law: the rising costs of fabrication, the limits of lithography, and the size of the transistor. Advantages of scaling: smaller, cheaper, and faster and to consume less power.

2. Quantum mechanics

Klassische Bewegungsgleichung: $m \frac{d^2 \mathbf{r}(t)}{dt^2} = \mathbf{F}$
 Classical wave equation:
 $\frac{1}{c^2} \frac{\partial^2 \Psi}{\partial t^2} - \sum_{i=1}^n \frac{\partial^2 \Psi}{\partial x_i^2} = 0$ $c = \lambda f$ $\omega = 2\pi f$ $k = \frac{2\pi}{\lambda}$ Waves
 behave as particles. Electrons and photons are both, particles and waves.
 Electron Orbits: $mvr = n\hbar$ $n\lambda = 2\pi r$
 Bohr atom model: $E_n \approx -13.6 \frac{Z^2}{n^2} \text{eV}$ Z : count of protons
 De Broglie Wavelength: $h = p\lambda$ $p = \hbar k$ $h = 2\pi\hbar$
 Uncertainty principle: $\Delta x \cdot \Delta p_x \geq \frac{\hbar}{2}$ $\Delta E \cdot \Delta t \geq \frac{\hbar}{2}$
 transistor dimension: $L_{crit} \approx \sqrt{\frac{\hbar}{2m^* E_b}} \approx 4 \text{ nm}$
 with $m^* \approx 0.19m_0$ $E_b = 0.5 \text{ eV}$

2.1. Schroedinger Equation

$$\left(\frac{-\hbar^2}{2m} \nabla^2 + V(\mathbf{r}, t) \right) \Psi(\mathbf{r}, t) = i\hbar \frac{\partial}{\partial t} \Psi(\mathbf{r}, t) \quad (1)$$

Potential energy $V(\mathbf{r}, t) \in \mathbb{R}$ (for Hydrogenatom $V(\mathbf{r}) = \frac{-e^2}{r}$)
 Hamiltonian $\hat{H} = \left(\frac{-\hbar^2}{2m} \nabla^2 + V(\mathbf{r}, t) \right)$
 Probabilitydensity $P(\mathbf{r}, t) = \Psi(\mathbf{r}, t) \cdot \Psi^*(\mathbf{r}, t) = |\Psi|^2$
 Normalized: $\int |\Psi(\mathbf{r}, t)|^2 d\mathbf{r} = 1$

2.1.1 time-independent Schroedinger equation

if $V(\mathbf{r}, t)$ is time-independent:
 $\Psi(\mathbf{r}, t) = \Psi(\mathbf{r}) \exp\left(\frac{iE t}{\hbar}\right) \Rightarrow \hat{H} \Psi(\mathbf{r}) = E \Psi(\mathbf{r})$
 1D Confinement (infinite Quantum Well):
 $\Psi_n(x) = \sqrt{\frac{2}{L_x}} \sin\left(\frac{\sqrt{2mE} x}{\hbar}\right)$
 $E_n = \frac{\hbar^2}{2m} k_n^2 = \frac{\hbar^2 \pi^2 n^2}{2mL^2}$

2D Confinement $\Psi(x, y) = \sqrt{\frac{4}{L_x L_y}} \sin(k_x x) \cdot \sin(k_y y)$
 $E_n = \frac{\hbar^2}{2m} (k_x^2 + k_y^2)$

δ -D Confinement with $\{i = x, y, \dots, \delta\}$
 $\Psi(\mathbf{r}) = \sqrt{\prod_{i=1}^{\delta} \frac{2}{L_i}} \prod_{i=1}^{\delta} \sin(k_i \cdot i)$
 $E_n = \frac{\hbar^2}{2m} (k_x^2 + k_y^2)$

Analytical solutions are only possible for the infinite quantum well

2.2. Quantenphysik

$$E_{Ph} = f \cdot h = \hbar \cdot \omega = \frac{\hbar c}{\lambda} \quad \boxed{\lambda \cdot \mathbf{p} = h}$$

$$p = \hbar k = \frac{\hbar k}{\lambda} \quad \hbar = \frac{h}{2\pi} \quad k = \frac{2\pi}{\lambda}$$

2.3. Phonons

are quasiparticles to describe modes of vibrations of elastic structures of interacting particles. there are acoustic and optical phonons.

3. Semiconductors

3.1. bandstructure

Fermienergie F_E : Höchste Energie eines Elektrons bei $T = 0 \text{ K}$ Isolator: große Bandlücke $E_G > 3 \text{ eV}$ Halbleiter: kleine Bandlücke $1 \text{ eV} < E_G < 3 \text{ eV}$ kann durch thermische Energie überwunden werden
 Materials in columns:
 IV: Si, Ge, III-V (GaAs, InP, GaN(BluRay), InSB), II-VI (CdSe, CsTe) IV-VI (PbS, PbSe)
 Silicon in crystal structure: 5 per Cube
 Chemical band structure: energylevels of different atoms moving close together
 At finite temperature some electrons can move around. $n \propto \exp(T_{bgap})$
 At 300K : $n = 1.5 \times 10^{10} \text{ cm}^{-3}$
 doping with donors(P,As) or acceptors(B,In) to lower the energy for emission or capture an electron
 atoms: 10^{23} per cm^3 , dopants: 10^{15} per cm^3

$$E_{kin} = \frac{p^2}{2m} = \frac{\hbar^2 k^2}{2m} \quad \frac{d^2 E}{dp^2} = \frac{1}{m}$$

$$\text{Effektiv mass: } \frac{1}{m_{eff}^*} = \frac{1}{\hbar} \cdot \frac{d^2 E}{dk^2}$$

Restorequation: $R_{Mat} = \rho_{Mat} \frac{l}{wt}$
 conductivity: $\sigma = \frac{1}{\rho} = q\mu n_i$
 resistivity: ρ

uncertainty for electron: $\Delta x \geq \frac{0.5 \cdot 10^{-4}}{\Delta v}$
 v_{sat} for Si: $2 \cdot 10^7 \frac{\text{cm}}{\text{s}}$
 $I_{DS} = \frac{1}{2} \mu C_{ox} \frac{W}{L} (V_{DD} - V_T)^2$
 $P = V_{DD}^2 C_{ox} f_{max}$

4. Transistors

$$I_D = \frac{1}{2} \mu_n C_{ox}' \frac{W}{L} \cdot (V_{GS} - V_{th})^2$$

$$\mu_n \approx 250 \cdot 10^{-4} \frac{\text{m}^2}{\text{Vs}}, \mu_p \approx 100 \cdot 10^{-4} \frac{\text{m}^2}{\text{Vs}}$$

$$P_{cap} = \alpha_{01} f C_{ox} V_{DD}^2$$

$$f_{max} = \frac{I_{sat}}{V_{DD} C_{ox}}$$

4.1. scaling with factor $S < 1$
 reduce area $A = W \cdot L$ $A' = A \cdot S^2$
 increase speed $\tau = \frac{L}{v}$ $\tau' = \tau \cdot S$
 reduce power $P = V I \tau$ $P' = P \cdot S^3$

Transistorscaling in nm: 90(2003), 65(2005), 45(2007), 32(2009), 22(2011)

- 4.1.1 Problem of scaling
1. Tunneling across the oxide
 2. Need for new lithographic techniques
 3. Parasitic effects due to interconnects
 4. Melting interconnects due to voids
 5. High field and breakdown effects
- \Rightarrow new materials, processes and technologies needed!

High-K Material (high dielectric ϵ) as Gate isolator: $\Rightarrow 1, 6 \cdot C_G, 0.01 \cdot I_{leak}$

Example Intels 45nm MOSFET: High-K with silicon gaten: Problems: uneven
 Form: Normalgate, Dualgate, Trigate
 Best: Surrounding Gate: CNT – high-K – metal-gate

4.2. Silicon Nanowire

Fabrication: growth on a gold(Au) particle

4.3. GaN - Transistors

Why GaN?

- Wide bandgaps of GaN and AlGaN (high breakdown volt.)
- high drift velocity(hf)
- strong piezoelectric effekt
- High temperature operation

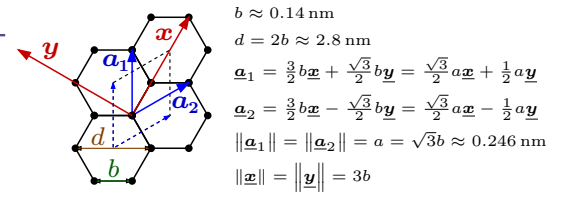
 HEMT-Transistor: Two substrate materials, doped and undoped
 \Rightarrow electrons move on a 2D-Sheet
 Cut-Off-Frequency $f_T = \frac{v_{sat}}{2\pi L_g}$: $g_m = 1$ (no amplification anymore)
 Oxide-Capacitance $C_{ox} = \frac{\epsilon_0 \epsilon_r}{t_{ox}}$
 T-Gate: smooth electric field in the channel.

4.4. Quantum Wire

Ideal: just one subband in two dimensions But for good conductance(mobility, drift velocity) one need 20nm Fabrication Methods: Stressor, Etching, Ion implantation, Vicinal Growth
 Split Gate Transistor: 1D tunnel in the gate between source and drain. electron wave transistor:

5. Graphene

2D Network of 3D Carbon Atoms.
 Stacked Layers of Graphene form Graphite.
 applications: separation membranes, capacitors



5.1. Properties

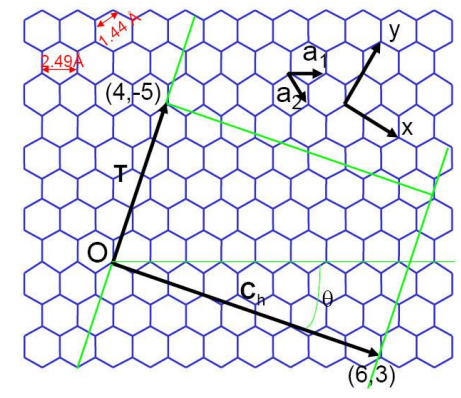
thinnest material sheet imaginable
 extremely strong (5 times stronger than steel)
 semimetal: better conduction than metal, can switched ON and OFF
 very light, good head conductor size of one cell: edge $d \approx 0.14 \text{ nm}$, edge2edge $a = \sqrt{3} d$

5.2. production

- Exfoliated Graphene: peeling HOPG with foil. Good for science not for manufacturing
- Epitaxial growth: silicon carbide(SiC) is heated ($> 1100^\circ \text{C}$) to reduce it to graphene.

5.3. Carbon-Nano-Tubes CNT

Properties: diameter: $d \approx 10 \text{ nm}$
 Application: wires, transistors, sensors, Molecular tweezers Single Walled and Multiwalled: SWCNT: single layer of graphite(graphene) rolled up as cylinder



Kind of Nanotube: $\begin{cases} \text{metallic} & \text{if } (n - m)/3 \in \mathbb{N}_0 \\ \text{semiconductor} & \text{else} \end{cases}$
 Bandenergy in dependency of \mathbf{k} :
 $E(\mathbf{k}) = \epsilon_0 \pm t \sqrt{1 + 4 \cos\left(\frac{\sqrt{3} a k_x}{2}\right) \cos\left(\frac{a k_y}{2}\right) + 4 \cos^2\left(\frac{a k_y}{2}\right)}$
 Periodic Boundary Conditions: $\mathbf{C}_h^\top \cdot \mathbf{k} = 2\pi n$